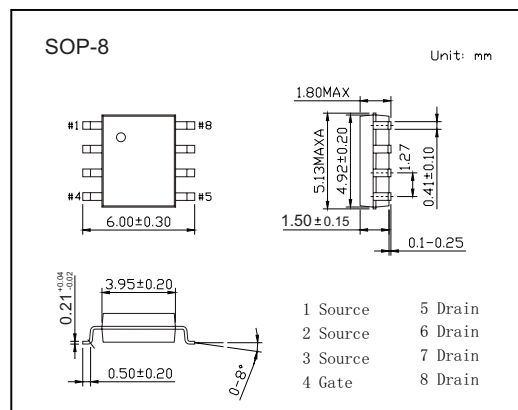


N-Channel MOSFET

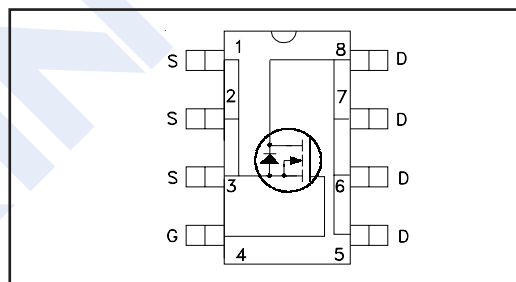
STS6NF20V

■ Features

- $V_{DS} (V) = 20V$
- $I_D = 6 A$
- $R_{DS(ON)} < 40m\Omega$ ($V_{GS} = 4.5V$)
- $R_{DS(ON)} < 45m\Omega$ ($V_{GS} = 2.7V$)
- Ultra Low Threshold Gate Drive
- Standard Outline For Easy Automated Surface Mount Assembly



INTERNAL SCHEMATIC DIAGRAM

■ Absolute Maximum Ratings $T_a = 25^\circ C$

Parameter	Symbol	Rating	Unit	
Drain-Source Voltage	V_{DS}	20	V	
Drain-Gate Voltage ($R_{GS} = 20k\Omega$)	V_{DGR}	20		
Gate-Source Voltage	V_{GS}	± 12		
Continuous Drain Current	I_D	$T_c = 25^\circ C$	6	A
		$T_c = 100^\circ C$	3.8	
Pulsed Drain Current	$I_{DM}^{(1)}$	24		
Total Dissipation	P_{tot}	2.5	W	
Thermal Resistance, Junction- to-Ambient	R_{thJA}	50	$^\circ C/W$	
Junction Temperature	T_J	150	$^\circ C$	
Storage Temperature Range	T_{stg}	-55 to 150		

1) Pulse width limited by safe operation area.

N-Channel MOSFET

STS6NF20V

■ Electrical Characteristics Ta = 25°C unless otherwise specified

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V _{DSS}	I _D =250 μA, V _{GS} =0V	20			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =18V, V _{GS} =0V			1	μA
		V _{DS} =18V, V _{GS} =0V, T _C =125°C			10	
Gate-Body Leakage Current	I _{GSS}	V _{DS} =0V, V _{GS} =±12V			±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250 μA	0.5		1	V
Static Drain-Source On-Resistance	R _{DS(on)}	V _{GS} =4.5V, I _D =3A			40	mΩ
		V _{GS} =2.7V, I _D =3A			45	
Forward Transconductance	g _{FS}	V _{DS} =15V, I _D =3A		10		S
Input Capacitance	C _{iss}	V _{GS} =0V, V _{DS} =15V, f=1MHz		460		pF
Output Capacitance	C _{oss}			200		
Reverse Transfer Capacitance	C _{rss}			50		
Turn-On DelayTime	t _{d(on)}	V _{DD} =10V, I _D =3A, R _G =4.7 Ω, V _{GS} =4.5V (Resistive Load, Figure 1)		7		ns
Turn-On Rise Time	t _r			33		
Turn-Off DelayTime	t _{d(off)}			27		
Turn-Off Fall Time	t _f			10		
Total Gate Charge	Q _g	V _{DD} =16V, I _D =6A, V _{GS} =4.5V (see test circuit, Figure 2)		8.5	11.5	nC
Gate Source Charge	Q _{gs}			1.8		
Gate Drain Charge	Q _{gd}			2.4		
Body Diode Reverse Recovery Time	t _{rr}	I _{SD} = 6A, di/dt = 100A/μs, V _{DD} =10V, T _j =150°C (see test circuit, Figure 3)		26		ns
Body Diode Reverse Recovery Charge	Q _{rr}			13		nC
Body Diode Reverse Recovery Current	I _{RRM}			1		A
Maximum Body-Diode Continuous Current	I _{SD}				6	A
Maximum Body-Diode Current (Pulsed)	I _{SDM} ¹⁾				24	
Diode Forward Voltage	V _{SD} ²⁾	I _{SD} =6A, V _{GS} =0V			1.2	V

1) Pulsed: Pulse duration = 300 μs, duty cycle 1.5%.

2) Pulse width limited by safe operation area.

■ Marking

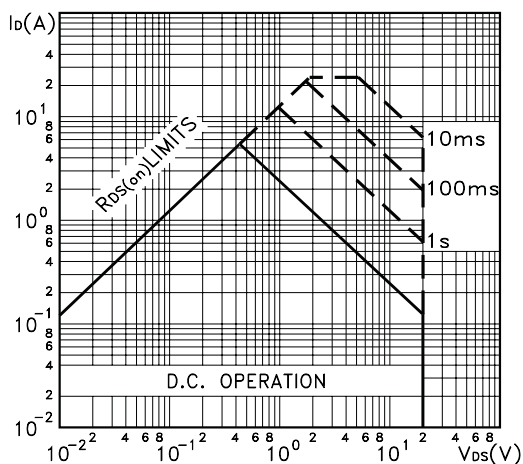
Marking	6N20V KC****
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N-Channel MOSFET

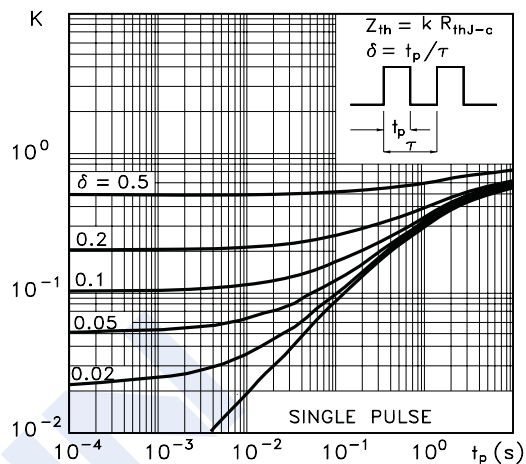
STS6NF20V

Typical Characteristics

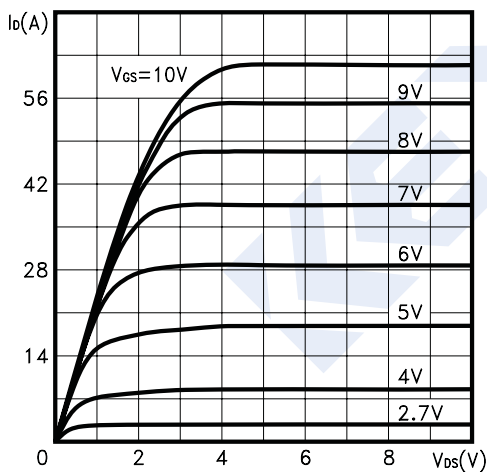
Safe Operating Area



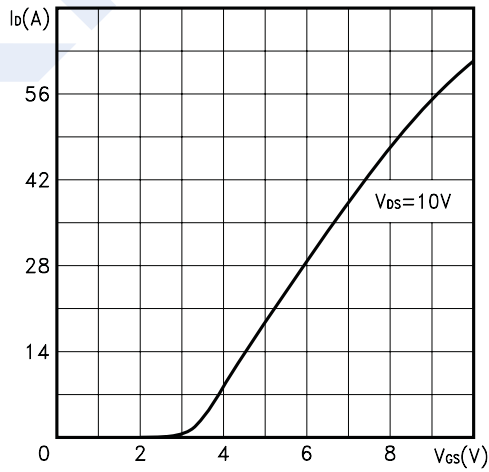
Thermal Impedance



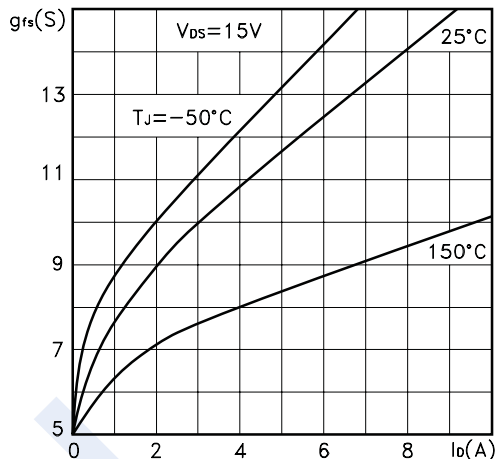
Output Characteristics



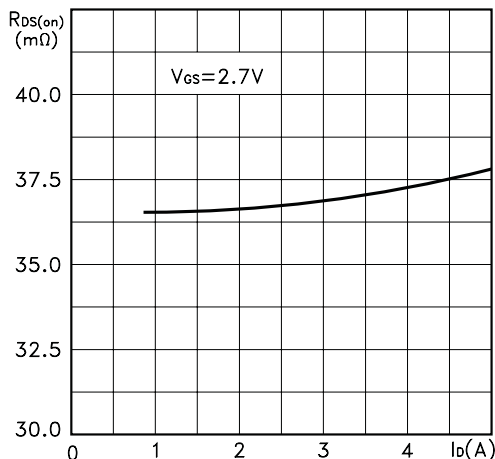
Transfer Characteristics



Transconductance



Static Drain-source On Resistance

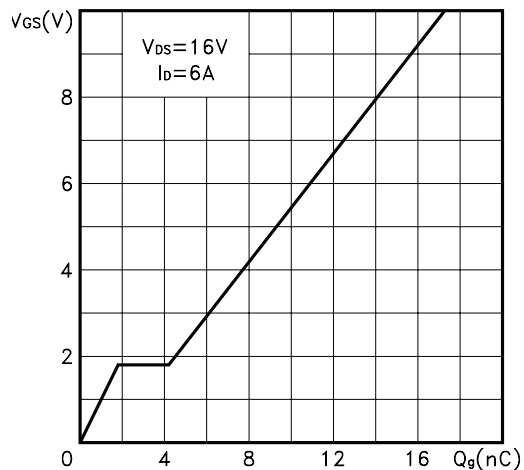


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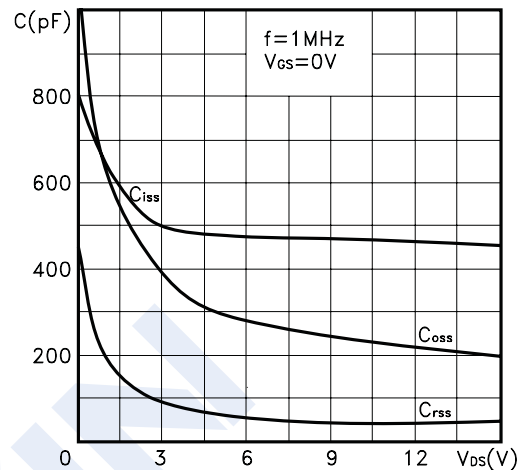
STS6NF20V

■ Typical Characteristics

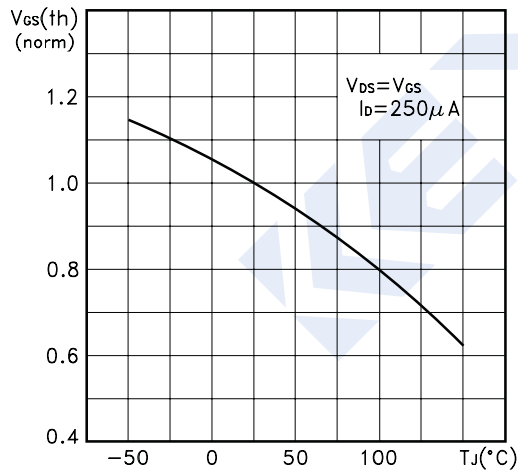
Gate Charge vs Gate-source Voltage



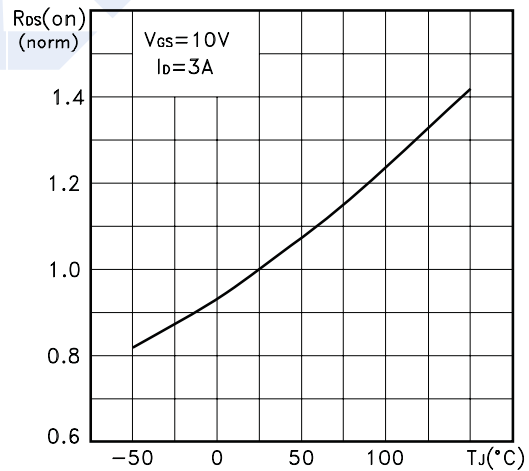
Capacitance Variations



Normalized Gate Threshold Voltage vs Temperature



Normalized on Resistance vs Temperature



Source-drain Diode Forward Characteristics

